

Docket No.: 60188-044

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Hirokazu YONEZAWA, et al.

Serial No.: 09/810,518

Group Art Unit:

Filed: March 19, 2001

Examiner:

For: APPARATUS AND METHOD FOR CALCULATING TEMPORAL DETERIORATION  
MARGIN AMOUNT OF LSI, AND LSI INSPECTION METHOD

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
Washington, DC 20231

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Supplemental Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Respectfully submitted,

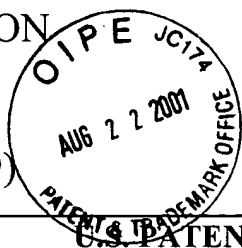
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INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION

(PTO-1449)



ATTY. DOCKET NO.  
**60188-044**

SERIAL NO.  
**09/810,518**

APPLICANT  
**Hirokazu YONEZAWA, et al.**

FILING DATE  
**March 19, 2001**

GROUP

## U.S. PATENT DOCUMENTS

| EXAMINER'S<br>INITIALS | PATENT NO. | DATE | NAME | CLASS | SUBCLASS | FILING DATE |
|------------------------|------------|------|------|-------|----------|-------------|
|                        |            |      |      |       |          |             |
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## FOREIGN PATENT DOCUMENTS

| EXAMINER'S<br>INITIALS | PATENT NO. | DATE | COUNTRY | CLASS | SUBCLASS | Translation |    |
|------------------------|------------|------|---------|-------|----------|-------------|----|
|                        |            |      |         |       |          | Yes         | No |
|                        |            |      |         |       |          |             |    |
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|                        |            |      |         |       |          |             |    |

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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|  | "Glacier User's Manual", BTA Technology, Inc., pp. 0-102, 1997-1998. |
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EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.